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ATTORNEY DOCKET NO.: D5116-00002

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of: Saxena et al.

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Serial No.: 09/675,427

JUN 20 2001

Filed: September 29, 2000

Technology Center 2100

For: Efficient Method for Modeling and Simulation of the Impact of Local and Global Variation on Integrated Circuits

I CERTIFY THAT THIS CORRESPONDENCE IS BEING DEPOSITED WITH THE U.S. POSTAL SERVICE AS FIRST CLASS MAIL IN AN ENVELOPE ADDRESSED TO THE ASSISTANT COMMISSIONER FOR PATENTS, WASHINGTON, D.C. 20231

ON June 13, 2001
Mary La Grange

Assistant Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

INFORMATION DISCLOSURE STATEMENT TRANSMITTAL LETTER

Enclosed herewith is an Information Disclosure Statement pursuant to 37 CFR.

§ 1.56 in connection with the above-identified application, which statement is being filed:

Together with the present application.

Before the first Office Action on the merits or three (3) months from the filing date of this application, whichever occurs last. [37 CFR § 1.97(b)]

- After the first Office Action on the merits, but before a Final Office Action under §1.113 or Notice of Allowance under §1.311, whichever occurs first. [37 CFR § 1.97(c)]
- After a Final Office Action under §1.113 or Notice of Allowance under §1.311, but prior to or with payment of the Issue Fee. [37 CFR § 1.97(d)]

Consistent with Applicant's obligations pursuant to 37 CFR §§1.97 and 1.98, the following requirements have been met:

- No separate requirements are needed.
- No additional fee is required.

[] Fee Under 37 CFR § 1.97(c) or 1.97(d)

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The fee of \$180.00 for submission of an IDS under § 1.97(c) as set forth in § 1.17(p) accompanies this statement.

[] Certification Under 37 CFR § 1.97(e)

The undersigned certifies:

- 1 that each item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the information disclosure statement; or
- 2 that no item of information contained in the information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application, and, to the knowledge of the person signing the statement after making reasonable inquiry, no item of information contained in the information disclosure statement was known to any individual designated in §1.56(c) more than three months prior to the filing of the information disclosure statement.

PATENT



ATTORNEY DOCKET NO.: D5116-00002

Provision of Copies of References

A copy of each of the references listed on the attached Form PTO-1449 is enclosed herewith and forms a part hereof.

A translation of Reference__ is enclosed herewith and forms a part hereof.

A copy of the European Search Report from a corresponding or related EPO application is enclosed herewith.

A copy of the International Search Report from a corresponding or related PCT application is enclosed herewith.

Identification of Prior Application(s) In Which Listed Information Was Already Cited And For Which No Copies Are Submitted Or Need Be Submitted

This application relies, under 35 U.S.C. § 120, on the earlier filing date of prior U.S. Application No(s). , filed . The following references were submitted to, and/or cited by, the Office in the prior application(s) and therefore are not required to be provided in this application:

The Commissioner is hereby authorized to charge any fees associated with this communication or credit any overpayment to Deposit Account No. 04-1679.

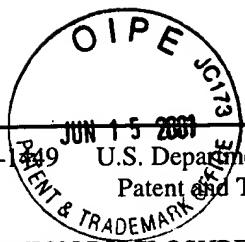
Respectfully submitted,

Date: June 13, 2001



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Form PTO-149 JUN 15 2001 U.S. Department of Commerce Patent and Trademark Office INFORMATION DISCLOSURE STATEMENT IN AN APPLICATION (Use several sheets if necessary)			Docket No. D5116-00002			Serial No. 09/675,427		
			Applicant Saxena et al					
			Filing Date Sept. 29, 2000			Group Art Unit 2812		
U.S. PATENT DOCUMENTS								
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	A	3,751,647	8/7/73	Maeder et al.	235	151.11		
	B	5,822,258	10/13/98	Casper	365	201		
	C	5,852,581	12/22/98	Beffa et al	365	201		
FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES NO	
OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)								
	D	Khare et al., "Yield Oriented Computer-Aided Defect Diagnosis", IEEE Trans. on Semiconductor Manufacturing, Vol. 8, No. 02, May 1995 (02.05.1995), pages 195-206						
	E	International Search Report dated 08 JUN 2001						
EXAMINER					DATE CONSIDERED			
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.								